

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Lademark Stitce	Attorney's Docket No. 12732-003001	Application No. 09/752,817		
	این losure Statement	Applicant Shunpei Yamazaki et al.			
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(37 CFR §1.98(b))		January 3, 2001	2073		
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Form PTO-1449

U.S. Department of Commerce
Patent and Trademark Office
Information Disclosure Statement by Applicant (Use several sheets if necessary)

Applicant Shunpei Yamazaki et al.

Filing Date January 3, 2001

Group Art Unit 2675

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Filing Date
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Group Art Unit 2675

(37 CFR §1.98(b))

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